## **Chip Scale Review**

## 2019 Editorial Calendar

(Editorial close date: 12/1/2018	January • February	Industry Events	
New test methodologies for 5G		APEX Expo     San Diego, CA (Jan 26-31)     3D & Systems Summit     Dresden, Germany (Jan 28-30)     SMTA Pan Pac Microelectronics     Symposium     Kauai, Hawaii (Feb 11-14)     FLEX / MEMS & Sensors Technical	
RF/OTA			
Low-temp direct bond interconnect			
Thermal debonding and warpage in FOWLP			
V2W/D2W & other bonding advances for 3D ICs		Congress Monterey, CA (Feb 18-21)	
Temporary bonding & the challenges of cleaning post debond			
3D IC metrology			
Discontinuities drive data integration			
Innovative materials & processes			
Stretchable interconnects			

## Ad Space Close Jan 18 - Ad Materials Close Jan 25

(Editorial close date: 1/15/19)	March • April	Industry Events		
SiP technology, drivers & market trends		TestConX Mesa, AZ (March 3-6)  IMAPS Device Packaging Fountain Hills, AZ (March 4-7)  SEMI-THERM San Jose, CA (March 18-22)  SEMICON China Shanghai, China (March 20-22)  ISS Europe Milan, Italy (March 31-April 2)		
3D system packaging				
Thin wafer handling				
High yield solutions for FOWLP				
Solders in semiconductor device assembly				
Hi-reliability standards		······································		
MEMS sensors				
Innovative microelectronic solutions				
OSAT new & emerging package offerings				

## Ad Space Close Mar 13 - Materials Close Mar 22

(Editorial close date: 3/8)	May • June	Industry Events
AI in packaging		SEMICON SE Asia     Kuala Lumpur, Malaysia (May 7-9)
Heterogeneous integration		• ECTC Las Vegas, NV (May 28-31)
Multi-die/ substrate heterogeneous packages		• IEEE/SW Test Workshop (SWTW) San Diego, CA (June 2-5 )
Reliability testing		• Sensors Expo San Jose, CA (June 25-27)
Automotive		• SEMICON West San Francisco, CA (July 9-11)
Inspection for advanced packaging processes	ection for advanced packaging processes	
RF, Final test		
Advances in wafer probe		
Smart devices and applications		